Applicant: Yoshiaki Togawa Serial No.: 10/077,616 Group Art Unit: 2977

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

- 1. (Currently Amended) A particle size distribution measuring apparatus comprising:
 - a sample cell capable of receiving particles therein;
- a light source section eapable of irradiating one two or more laser lights having a plurality of wavelengths to the <u>sample cell</u>;

a detector capable of measuringconfigured to measure the intensity of a direct light passing through the <u>sample</u> cell and light scattered by said particles at respective scattering angles; and

an arithmetic processing section capable of determiningconfigured to determine the particle size distribution by using the laser light at a first wavelength for the region of the particle size having low sensitivity, and a laser light at a second wavelength in the whole range of the particle size to be measured to compensate the sensitivity of the region be measured by the detectors.

- 2. (Original) The apparatus of claimed 1 wherein said light source section further comprises a plurality of light sources capable of irradiating laser lights at a plurality of different wavelengths.
- 3. (Currently Amended) The apparatus as claimed 1 wherein said detector is capable of measuringconfigured to measure the intensity of the direct light and light scattered by said particles at respective scattering angles irrespective of the wavelength of the laser light.
- 4. (Currently Amended) The apparatus of claim 1 where said light source is capable of irradiating-irradiates laser light at plurality of wavelengths sequentially.

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- 5. (Currently Amended) The apparatus of claim1 further comprising a shutter eapable of configured to transmitting laser light of a selected wavelength and preventing the transmission of laser light at another wavelength.
- 6. (Original)The apparatus of claim 1 wherein said light source section irradiates a first laser light having a first wavelength and at least a second laser light having a second wavelength, wherein said first wavelength is at least 1.5 times larger than said second wavelength.